

Living up to Life

Leica
MICROSYSTEMS

Cross-section of SiC abrasive paper

Clay, imaged by Lukas Keller, EMPA Switzerland

Cross-section of veneer

High Quality Surface Finishing Meets Versatility

Leica EM TIC 3X – Triple Ion-Beam Cutter

- Large surface preparation (exceeding 4 x 1 mm)
- Interchangeable stages
- High sample throughput design – multiple sample holder
- Precise targeting and observation system
- Cooling stage for heat-sensitive samples

www.leica-microsystems.com

